CMOS 8-Stage Static Shift Register

Asynchronous Parallel Input/Serial Output,
Synchronous Serial Input/Serial Output

The RCA-CD4021A types are 8-stage parallel or serial-input/serial-output shift registers having common CLOCK and PARALLEL/SERIAL CONTROL inputs, a single SERIAL DATA input, and individual parallel Jam inputs to each register stage. Each register stage is a D-type, master-slave flip-flop. Q outputs are available from the sixth, seventh, and eighth stages.

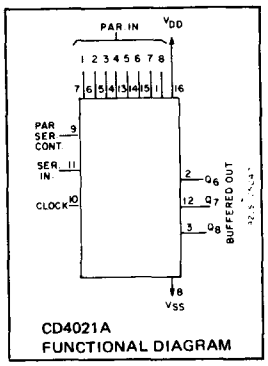
When the PARALLEL/SERIAL CONTROL input is low, data are serially shifted into the 8-stage register synchronously with the positive-going transition of the CLOCK pulse.

Features:

- **Asynchronous parallel or synchronous serial operation under control of parallel/serial control-input**
- **Individual JAM inputs to each register stage**
- **Master-slave flip-flop register stages**
- **Fully static operation. . . . . DC to 5 MHz**
- **Quiescent current specified to 15 V**
- **Maximum input leakage current of 1 μA at 15 V (full package-temperature range)**
- **1-V noise margin (full package-temperature range)**

When the PARALLEL/SERIAL CONTROL input is high, data are jammed into the 8-stage register via the parallel input lines asynchronously with the clock line.

Register expansion is possible using additional CD4021A packages.



CD4021A
FUNCTIONAL DIAGRAM

These types are supplied in 16-lead hermetic dual-in-line ceramic packages (D and F suffixes), 16-lead dual-in-line plastic package (E suffix), 16-lead ceramic flat package (K suffix), and in chip form (H suffix).

Applications:

- **Parallel to serial data conversion**
- **Asynchronous parallel input/serial output data queueing**
- **General purpose register**

STATIC ELECTRICAL CHARACTERISTICS

CHARACTERISTICS	CONDITIONS			LIMITS AT INDICATED TEMPERATURES (°C)								UNITS
				D, F, K, H PACKAGES				E PACKAGE				
	V_O (V)	V_{IN} (V)	V_{DD} (V)	-55	+25 TYP.	+25 LIMIT	+125	-40	+25 TYP.	+25 LIMIT	+85	
Quiescent Device Current I_L Max.	–	–	5	5	0.5	5	300	50	0.5	50	700	μA
	–	–	10	10	1	10	600	100	1	100	1400	
	–	–	15	50	1	50	2000	500	5	500	5000	
Output Voltage: Low-Level, V_{OL}	–	5	5	0 Typ.; 0.05 Max.								V
	–	10	10	0 Typ.; 0.05 Max.								
High Level V_{OH}	–	0	5	4.95 Min.; 5 typ.								
	–	0	10	9.95 Min.; 10 Typ.								
Noise Immunity; Inputs Low, V_{NL}	4.2	–	5	1.5 Min.; 2.25 Typ.								V
	9	–	10	3 Min.; 4.5 Typ.								
Inputs High V_{NH}	0.8	–	5	1.5 Min.; 2.25 Typ.								
	1	–	10	3 Min.; 4.5 Typ.								
Noise Margin: Inputs Low, V_{NML}	4.5	–	5	1 Min.								V
	9	–	10	1 Min.								
Inputs High, V_{NMH}	0.5	–	5	1 Min.								
	1	–	10	1 Min.								
Output Drive Current: N-Channel (Sink), $I_D N$ Min.	0.5	–	5	0.15	0.3	0.12	0.085	0.072	0.3	0.06	0.05	mA
	0.5	–	10	0.31	0.5	0.25	0.175	0.12	0.5	0.1	0.08	
P-Channel (Source) $I_D P$ Min.	4.5	–	5	-0.1	-0.16	-0.08	-0.055	-0.06	-0.16	-0.05	-0.04	
	9.5	–	10	-0.25	-0.44	-0.20	-0.14	-0.12	-0.44	-0.1	-0.08	
Input Leakage Current, I_{IL}, I_{IH}	Any Input											
	–	–	15	$\pm 10^{-5}$ Typ., ± 1 Max.								

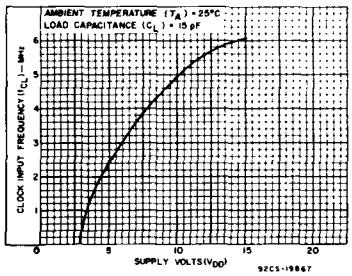


Fig. 1 – Typical clock input frequency vs. supply voltage.

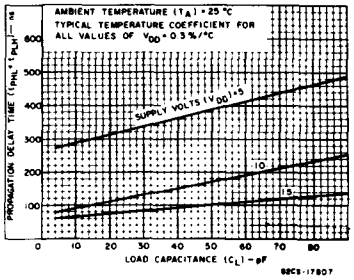


Fig. 2 – Typical propagation delay time vs. load capacitance.

CD4021A Types

MAXIMUM RATINGS, *Absolute-Maximum Values:*

STORAGE-TEMPERATURE RANGE (T_{stg}) . . . . . −65 to +150°C

OPERATING-TEMPERATURE RANGE (T_A)

PACKAGE TYPES D, F, K, H . . . . . −55 to +125°C

PACKAGE TYPE E . . . . . −40 to +85°C

DC SUPPLY-VOLTAGE RANGE, (V_{DD})

(Voltages referenced to V_{SS} Terminal) . . . . . −0.5 to +15 V

POWER DISSIPATION PER PACKAGE (P_D)

FOR T_A = −40 to +60°C (PACKAGE TYPE E) . . . . . 500 mW

FOR T_A = +60 to +85°C (PACKAGE TYPE E) . . . . . Derate Linearly at 12 mW/°C to 200 mW

FOR T_A = −55 to +100°C (PACKAGE TYPES D, F, K) . . . . . 500 mW

FOR T_A = +100 to +125°C (PACKAGE TYPES D, F, K) . . . Derate Linearly at 12 mW/°C to 200 mW

DEVICE DISSIPATION PER OUTPUT TRANSISTOR

FOR T_A = FULL PACKAGE-TEMPERATURE RANGE (ALL PACKAGE TYPES) . . . . . 100 mW

INPUT VOLTAGE RANGE, ALL INPUTS . . . . . −0.5 to V_{DD} +0.5 V

LEAD TEMPERATURE (DURING SOLDERING):

At distance 1/16 ± 1/32 inch (1.59 ± 0.79 mm) from case for 10 s max. . . . . +265°C

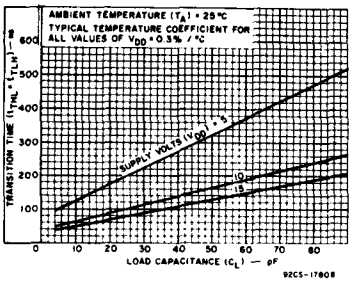


Fig. 3 — Typical transition time vs. load capacitance.

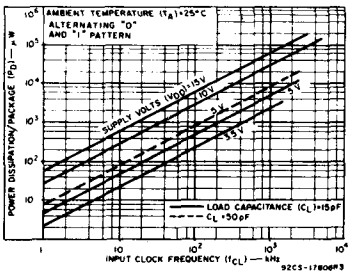


Fig. 4 — Typical dissipation characteristics.

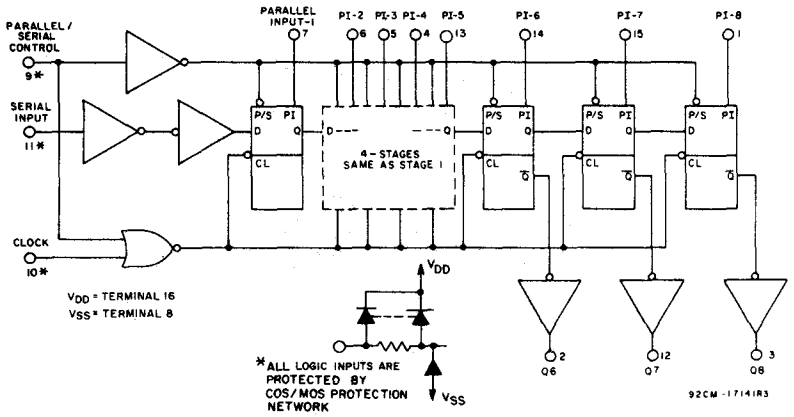


Fig. 5 — Logic diagram.

TRUTH TABLE

CL▲	Serial Input	Parallel/ Serial Control	PI-1	PI-n	Q_1 (Internal)	Q_n
X	X	1	0	0	0	0
X	X	1	0	1	0	1
X	X	1	1	0	1	0
X	X	1	1	1	1	1
⌐	0	0	X	X	0	Q_{n-1}
⌐	1	0	X	X	1	Q_{n-1}
⌐	X	0	X	X	Q_1	Q_n

▲ = LEVEL CHANGE X = DON'T CARE CASE

NO CHANGE

92CS-17141R3

Fig. 6 — Truth table.

RECOMMENDED OPERATING CONDITIONS *at T_A = 25°C, Except as Noted. For maximum reliability, nominal operating conditions should be selected so that operation is always within the following ranges:*

CHARACTERISTIC	VDD (V)	LIMITS				UNITS
		D, F, K, H PACKAGES		E PACKAGE		
		MIN.	MAX.	MIN.	MAX.	
Supply-Voltage Range (For T_A=Full Package-Temperature Range)		3	12	3	12	V
Data Setup Time, t_S	5	350	–	500	–	ns
	10	80	–	100	–	
Clock Pulse Width, t_W	5	500	–	830	–	ns
	10	175	–	200	–	
Clock Input Frequency, f_{CL}	5	dc	1	dc	0.6	MHz
	10	dc	3	dc	2.5	
Clock Rise and Fall Time, t_rCL, t_fCL*	5	–	15	–	15	μs
	10	–	5	–	5	

*If more than one unit is cascaded t_rCL should be made less than or equal to the sum of the transition time and the fixed propagation delay of the output of the driving stage for the estimated capacitive load.

DYNAMIC ELECTRICAL CHARACTERISTICS

at $T_A = 25^oC$, Input t_r, $t_f = 20$ ns, $C_L = 15$ pF, $R_L = 200$ kΩ

CHARACTERISTIC	TEST CONDITIONS	LIMITS						UNITS
		D, F, K, H PACKAGES			E PACKAGE			
	VDD (V)	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.	
Propagation Delay Time,** t_{PLH}, t_{PHL}	5	–	300	750	–	300	1000	ns
	10	–	100	225	–	300	300	
Transition Time; t_{THL}, t_{TLH}	5	–	150	300	–	150	400	ns
	10	–	75	125	–	75	150	
Maximum Clock Input Frequency, f_{CL}	5	1	2.5	–	0.6	2.5	–	MHz
	10	3	5	–	2.5	5	–	
Minimum Clock Pulse Width, t_W	5	–	200	500	–	200	830	ns
	10	–	100	175	–	100	200	
Clock Rise & Fall Time; t_rCL & t_fCL*	5	–	–	15	–	–	15	μs
	10	–	–	5	–	–	5	
Minimum Data Set Up Time, t_S	5	–	100	350	–	100	500	ns
	10	–	50	80	–	50	100	
Minimum High-Level Parallel/Serial Control Pulse Width t_W	5	–	200	500	–	200	830	ns
	10	–	100	175	–	100	200	
Input Capacitance C_I	Any Input	–	5	–	–	5	–	pF

*If more than one unit is cascaded t_rCL should be made less than or equal to the sum of the transition time and the fixed propagation delay of the output of the driving stage for the estimated capacitive load.

**From Clock or Parallel/Serial Control Input

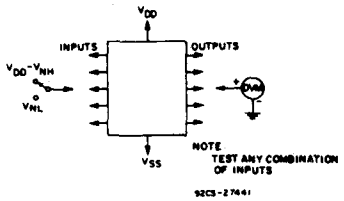


Fig. 7 – Noise-immunity test circuit.

Test performed with the following sequence of "One's" and "Zero's".

S_1	S_2	S_3	S_4	S_5
0	0	1	0	0
1	0	1	1	1
1	0	1	0	1
0	1	1	1	1
0	1	0	0	0

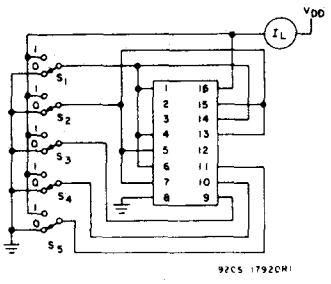


Fig. 8 – Quiescent device current test circuit.

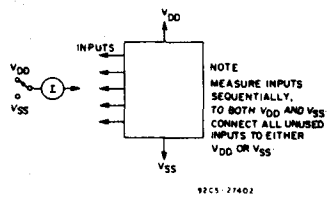


Fig. 9 – Input-leakage-current test circuit.

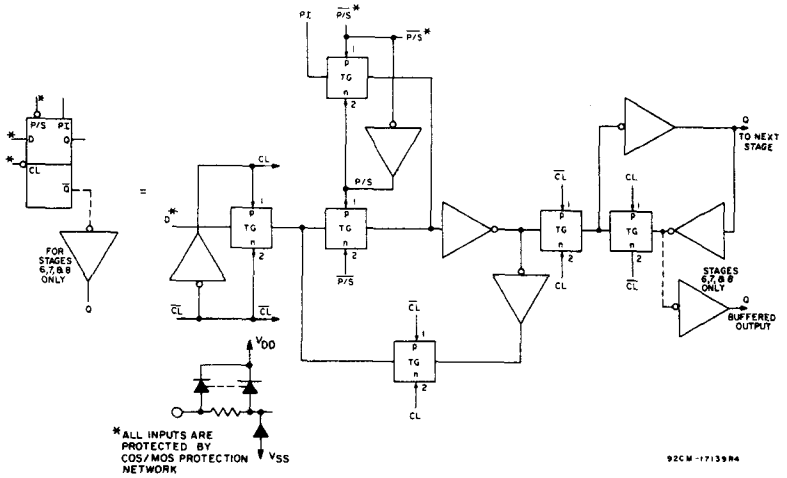


Fig. 10 – One typical stage and its equivalent detailed circuit.